


<b>Search Notes</b>  	<b>Application/Control No.</b>  10539211	<b>Applicant(s)/Patent Under Reexamination</b>  WANG ET AL.
	<b>Examiner</b>  Hevey, John A	<b>Art Unit</b>  1709

SEARCHED			
Class	Subclass	Date	Examiner
252	62	7/19/07, 11/29/07	JAH
524	413	7/19/07, 11/29/07	JAH
423	594.9	11/29/07	JAH

SEARCH NOTES		
Search Notes	Date	Examiner
East - see search history	7/19/07, 11/29/07	JAH
Inventor search in PALM	7/19/07, 11/29/07	JAH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner